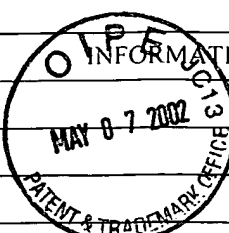


U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					CT-M158 US		09/896,249	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicants			
(Add additional sheets if necessary)					Pei, Shiyu, et al.			
					Filing Date		Group	
					June 28, 2001		2879	
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
KJN	AA	4,919,157	04/24/90	Mateias	134	2		
	AB	5,559,389	09/24/96	Spindt et al.	313	310		
	AC	5,564,959	10/15/96	Spindt et al.	445	24		
	AD	5,605,484	02/25/97	Bailey et al.	445	59		
	AE	5,635,790	06/03/97	Meyer et al.	313	309		
	AF	5,853,492	12/29/98	Cathey et al.	134	3		
	AG	5,977,706	11/02/99	Cho et al.	313	553		
	AH	6,004,180	12/21/99	Knall et al.	445	59		
	AI	6,113,708	09/05/00	Hopple et al.	134	7		
	AJ	6,139,390	10/31/00	Pothoven et al.	445	41		
KJN	AK	US 6,187,603 B1	02/13/01	Haven et al.	438	20		
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AS							
	AT							
	AU							
	AV							
	AW							
Examiner		<b>PRIMARY EXAMINER</b> KENNETH J. RAMSEY		Date Considered		7/11/03		
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		Pei, Shiyu, et al.	
		Filing Date	Group
		June 28, 2001	2879
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
14/12	AA	Brodie, et al., "Vacuum Microelectronics," <u>Advances In Electronics And Electron Physics</u> , Vol. 83, 1992, pp. 1 - 106.	
	AB	Chalamala, et al., "Operation of FEAs in Hydrogen and the Development of Thin Film Metal Hydrides for Integration into FEDs", <u>SID 01 Digest</u> , 2001, pp. 89 - 91.	
	AC	Chalamala, et al., "Residual Gas Effects on the Emission Characteristics of Active Mo Field-Emission Cathode Arrays," <u>SID 98 Digest</u> , 1998, pp. 107 - 110.	
	AD	Chalamala, et al., "Surface conditioning of active molybdenum field emission cathode arrays with H <sub>2</sub> and helium," <u>J. Vac. Sci. Technol.</u> , Sept/Oct 1998, pp. 2855 - 2858.	
	AE	Hopple, et al., "FED Life and Reliability," <u>Information Display</u> , April/May 2000, pp. 34 - 37.	
	AF	Jo, et al., "Analysis of field emission characteristics of hydrogen-adsorbed silicon surface," <u>Appl. Phys. Lett.</u> , 15 April 1996, pp. 2234 - 2236.	
	AG	Kim, et al., "High-Resolution 5-8in. Full-Color FEDs with New Aging Technique," <u>Proceedings of SID'98</u> , Int'l. Symp., 17 - 22 May 1998, 4 pgs.	
	AH	Reuss, et al., "New Insights Into the Degradation of Field Emission Displays," <u>SID 01 Digest</u> , 2001, pp. 81 - 83.	
K/12	AI	Schwoebel, et al., "Field-emitter array performance enhancement using hydrogen glow discharges," <u>Appl. Phys. Lett.</u> , July 1993, pp. 33 - 35.	
	AJ		
	AK		
	AL		
	AM		
Examiner		Date Considered	
KENNETH J. RAMSEY PRIMARY EXAMINER		7/11/03	
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